

Message Text

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70

ORIGIN EB-07

INFO OCT-01 CIAE-00 COME-00 DODE-00 NRC-05 NSAE-00 USIA-06

TRSE-00 EUR-12 ERDA-05 ISO-00 ACDA-07 MC-02 /045 R

DRAFTED BY EB/ITP/EWT:LROSS

APPROVED BY EB/ITP/EWT:RWPRACHT

COMMERCE/OEA:MHUTCHINSON

DEFENSE/OSD:LJAMES

RPE

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P 122212Z JUL 76

FM SECSTATE WASHDC

TO USMISSION OECD PARIS PRIORITY

C O N F I D E N T I A L STATE 172100

EXCON

E.O. 11652: XGDS-1

TAGS: ESTC, COCOM, CH, JA

SUBJECT: JAPANESE IC TESTER TO CHINA - IL 1355

REFS: A) OECD PARIS 18171, B) COCOM DOC (76)780

OBJECT TO IC TESTER. IT IS CAPABLE OF PRECISION TESTING AND MEASURING OF LINEAR IC'S DURING SCREENING OF FINISHED PACKAGED DEVICES AT CONCLUSION OF PRODUCTION PROCESS. EVEN IF NOT CAPABLE OF INTERFACING WITH AUTOMATIC HANDLER, WAFER PROBER, ETC., INSTRUMENT IS NEVERTHELESS CAPABLE OF PRODUCTION TESTING OF 4000 TO 8000 FINISHED IC'S PER EIGHT HOUR SHIFT. IN ADDITION THE TESTER'S SCREENING CAPABILITY IS ENHANCED BY VIRTUE OF ADDITIONAL FEATURES LISTED IN THE SUPPLIED BROCHURE WHICH INCLUDE DIGITAL TEST READOUT AND POSSIBLE BCD OUTPUT PROCESSING. PERFORMANCE TESTING OF IC'S AND OTHER SPARES FOR INDIVIDUAL COMPUTER INSTALLATIONS IS NORMALLY PERFORMED BY THE MANUFACTURER RATHER THAN BY

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USERS OF THE COMPUTERS AND PARTS IN QUESTION. KISSINGER

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NNN

Message Attributes

Automatic Decaptioning: X
Capture Date: 01 JAN 1994
Channel Indicators: n/a
Current Classification: UNCLASSIFIED
Concepts: ELECTRONIC EQUIPMENT, STRATEGIC TRADE CONTROLS, EXCEPTIONS LIST
Control Number: n/a
Copy: SINGLE
Draft Date: 12 JUL 1976
Decaption Date: 01 JAN 1960
Decaption Note:
Disposition Action: RELEASED
Disposition Approved on Date:
Disposition Authority: KelleyW0
Disposition Case Number: n/a
Disposition Comment: 25 YEAR REVIEW
Disposition Date: 28 MAY 2004
Disposition Event:
Disposition History: n/a
Disposition Reason:
Disposition Remarks:
Document Number: 1976STATE172100
Document Source: CORE
Document Unique ID: 00
Drafter: LROSS
Enclosure: n/a
Executive Order: X1
Errors: N/A
Film Number: D760268-0592
From: STATE
Handling Restrictions: n/a
Image Path:
ISecure: 1
Legacy Key: link1976/newtext/t19760767/aaaacgro.tel
Line Count: 61
Locator: TEXT ON-LINE, ON MICROFILM
Office: ORIGIN EB
Original Classification: CONFIDENTIAL
Original Handling Restrictions: n/a
Original Previous Classification: n/a
Original Previous Handling Restrictions: n/a
Page Count: 2
Previous Channel Indicators: n/a
Previous Classification: CONFIDENTIAL
Previous Handling Restrictions: n/a
Reference: 76 OECD PARIS 18171
Review Action: RELEASED, APPROVED
Review Authority: KelleyW0
Review Comment: n/a
Review Content Flags:
Review Date: 21 APR 2004
Review Event:
Review Exemptions: n/a
Review History: RELEASED <21 APR 2004 by CunninFX>; APPROVED <17 AUG 2004 by KelleyW0>
Review Markings:

Margaret P. Grafeld
Declassified/Released
US Department of State
EO Systematic Review
04 MAY 2006

Review Media Identifier:
Review Referrals: n/a
Review Release Date: n/a
Review Release Event: n/a
Review Transfer Date:
Review Withdrawn Fields: n/a
Secure: OPEN
Status: NATIVE
Subject: JAPANESE IC TESTER TO CHINA - IL 1355
TAGS: ESTC, CH, JA, US, COCOM
To: OECD PARIS
Type: TE
Markings: Margaret P. Grafeld Declassified/Released US Department of State EO Systematic Review 04 MAY 2006